Form 1449 (Modified) Atty Docket No. LAM1P124D1 Application No.: Not Yet Assigned Information Disclosure Statement By Applicant Filing Date Art Group Unit Unknown Page 1 of 1

U.S. Patent Documents

			U.S. Faten	t Documents			
Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
Elm	Α.	4,690,793	09/1987	"Hitachi, Ltd. et al."			
	B.	4,948,458	08/1990	Ogle	\		
	C.	4,990,229	02/1991	Campbell et al.			
	D.	5,091,049	02/1992	Campbell et al.			
	E.	5,122,251	06/1992	Campbell et al.			
	F.	5,242,264	09/1993	Kojima et al.			
	G.	5,356,661	10/1994	Doi et al.		X	
	H.	5,421,891	06/1995	Campbell et al.			
	1.	5,429,070	07/1995	Campbell et al.		/	
	J.	5,587,038	12/1996	Cecchi et al.	7		
	K.	5,788,799	08/1998	Steger et al			
	L.	5,885,356	03/1999	Zhao et al.			
	M.	6,063,199	05/2000	Sajoto et al.	1/-		
1	N.	6,165,271	12/2000	Zhao et al.	1/		
1	1		1				

Foreign Patent or Published Foreign Patent Application

		-		•	•		
Examiner Initial		Document No.	Publication Date	Country or Patent Office	Class	Sub- Class	Translation Yes No
Dispill	O.	0 819 780 A2	01/1998	EPO			
i	P.	0 837 489 A2	04/1998	EPO			
	Q.	0 838 842 A2	04/1998	EPO			\times
	R.	0 838 843 A2	04/1998	EPO			
7	S.	JP61-104291	05/1986	Japan			

Other Documents

Examiner Initial	No.	Author, Title, Place (e.g. Journ						
REAM	T.	Y. Fujiwara et al., "Temperatu seeded volume negative ion so	7. Fujiwara et al., "Temperature control of plasma grid for continuous operation in cesium- ceded volume negative ion source," Rev. Sci. Inst. 69 (2), 2.98, pp. 1173-1175.					
	U.	Mizuhara et al., "Ceramic/Met 210.	al Seals," Engineering Materials Handbook, 11.95, pp. 502-					
$\overline{}$	V.	D.R. Write et al., "Low tempe transfer and wafer temperature	rature etch chuck: Modeling and experimental results of heat ," J. Vac. Sci. Technol. A 10 (4), 7.92, pp. 1065-1070.					
Examiner	X	ij andin	Date Considered $C4/03/02$					

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LAM1P124D1 Atty Docket No. Form 1449 (Modified) DEC 1 2 2001 09/943.806 Application No.: BAILEY III et al. Applicant Information Discosure 08/30/2001 Statement By Applicant By Filing Date 1763 Group (Use Several Sheets if Necessary)

			U.S. Pater	Class	Sub-	Filing Dat	
Examiner	No.	Patent No.	Date	Patentee		class	
Initial	-	5,707,452	01/1998	Dandl			
PAUL	A. B.	5,795,451	08/1998	Tan et al.			
	C.	6.113.731	09/2000	Shan et al.			
	$\frac{C}{D}$	6.178.920	01/2001	Ye et al.			
	$\frac{1}{E}$	6.196.155	03/2001	Setoyama et al.			
<u> </u>							

Foreign Patent or Published Foreign Patent Application

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	Foreign Patent of	Published 1 of	Country or	Class	Sub-	Translation
	Document No.		Patent Office		Class	Yes No
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	Other Documents
Examiner Initial	No. Author, Title, Place (e.g. Journal) of Publication, Date J.
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	M. N.
	0.
Examiner	Date Considered (U3/U2 2 5) Little Station considered. Draw line through citation if not in conformance and applicant.

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